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REFERENCES

1. The simpliest acoustic switch [The electronic resource]- http://vrtp.ru/index.php?showtopic=8574 – (date of watching:25.03.2015)
2. Acoustic switch as easy as pie [The electronic resource]- http://www.sdelaysam-svoimirukami.ru/620-akusticheskiy-vyklyuchatel-prosche-prostogo.html – (date of watching:05.04.2015)

SIMPLE PHYSICAL MODELS IN PRACTICAL APPLICATIONS FOR NEW ENGINEERING TASKS

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There is a traditional opinion that modern physics can evolve only by using more and more complex mathematical and physical models. In practice, this often appears as division of a single common problem to multiple small problems with complex description. In this case, complete picture of actual process can be lost in a huge amount of practically unimportant details. Sometimes the simplified description is better, when more understandable global description is more preferable compared with more precise, but also more complex for understanding physical models. We describe a few simple models that can be applied in the practical engineering to understand the basic behavior of modern semiconductor devices.

Various types of detectors with internal amplification of weak signals produced by ionizing radiation are used in modern physical experiments. There is a large class of gaseous detectors and presently widely used semiconductor avalanche photo detectors (APDs) [1]. Avalanche physical processes in semiconductors are more complex to describe and understand compared with simple Tungsten model for avalanche in gaseous detectors. However, it is not necessary to solve the fundamental system of partial differential equations to understand the processes in this type of detectors. Well known by radio engineers common conception of feedback can be applied for simple description of such a complex system [2]. Simple feedback model can be used for the classification of different types of modern APDs and for description of its internal processes. Simple "Logistic" model is applied to explain how the rising time of avalanche depends on the probability of avalanche occurrence in the APD. To understand how carriers generation-recombination processes are affected by traps created during irradiation and self annealing in semiconductors, one can apply a simple model based on assumption of a single traps level and a single lifetime of carriers on this level [3]. Interpretation of results obtained for a few types of commercial APDs is presented. Example of method of the detector noise introduction applied to the detector SPICE model is discussed. In addition, simple SPICE model describing gain coefficient and applicable for transient analysis of APD is proposed.

REFERENCES

1. Kushpil V. Avalanche Process in Semiconductor Photo Detectors in the Context of the Feedback Theory / Chapter 10 in book "Photodetectors" edited by Sanka Gateva,– InTech Publisher, 2012. – 470 p.
2. Kushpil V.V. Application of simple negative feedback model for avalanche photodetectors investigation// Nuclear Instruments and Methods in Physics Research A. – 2009. – N. 610. – P. 204–206.
3. Kushpil V., Mikhaylov V., Kushpil S., Tlustý P., Svoboda O., Kugler A. Radiation hardness investigation of avalanche photodiodes for the Projectile Spectator Detector readout at the Compressed Baryonic Matter experiment // Nuclear Instruments and Methods in Physics Research A. – 2014. – doi:10.1016/j.nima.2014.11.071.